## 

## +3.3V, 2.5Gbps, SDH/SONET, 4-Channel Interconnect Mux/Demux ICs with Clock Generator

#### **General Description**

The MAX3831/MAX3832 are 4:1 multiplexers (muxes) and 1:4 demultiplexers (demuxes) with automatic channel alignment. Operating from a single +3.3V supply, the mux receives four parallel, 622Mbps SDH/SONET channels. These channels are bit interleaved to generate a serial data stream of 2.488Gbps for interfacing to an optical or an electrical driver. A 10-bit-wide elastic buffer tolerates up to ±7.5ns skew between any parallel data input and the reference clock. An external 155MHz reference clock is required for the on-chip PLL to synthesize a high-frequency 2.488GHz clock for timing the outgoing data streams.

The MAX3831/MAX3182's demux receives 2.488Gbps serial data and the 2.488GHz clock from an external clock/data recovery device (MAX3876), converting it to four 622Mbps LVDS outputs. The MAX3831 provides a 622MHz LVDS clock output, and the MAX3832 provides a 155MHz LVDS clock output. An internal frame detector looks for a 622Mbps SDH/SONET framing pattern and rolls the demux to maintain proper channel assignment at the outputs.

These devices also include an embedded pattern generator that enables a full-speed, built-in self-test (BIST). Two different loopback modes provide system test flexibility. A TTL loss-of-frame monitor is included. The MAX3831/MAX3832 are available in 64-pin TQFP-EP (exposed paddle) packages and are specified over the upper commercial (0°C to +85°C) temperature range.

Pin Configuration appears at end of data sheet.

#### **+3.3V Single Supply**

- **♦ 1.6W Power Dissipation**
- ♦ 4-Channel Mux/Demux with Fully Integrated 2.488GHz Clock Generator
- **♦** Frame Detection Maintains Channel Assignment
- ♦ 2.5ps RMS Serial-Data Output Random Jitter
- ♦ 8ps Serial Data Output Deterministic Jitter
- ♦ 622Mbps LVDS Parallel Input/Output
- ♦ 2.488Gbps Serial CML Input/Output
- On-Chip Pattern Generator Provides **High-Speed BIST**
- **♦** System Test Flexibility: System Loopback, Line Loopback
- ♦ Loss-of-Frame Indicator

#### **Applications**

Features

SDH/SONET Backplanes High-Speed Parallel Links Line Extenders

Intrarack/Subrack Interconnects

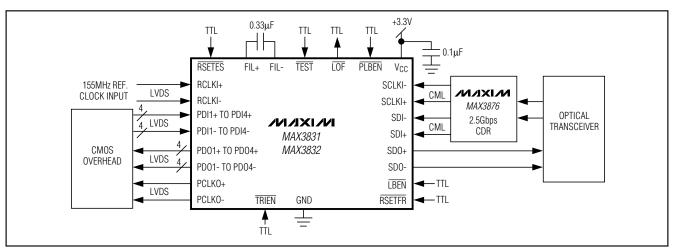
ATM Switching Networks Dense Digital Cross-Connects

## **Ordering Information**

PART	TEMP. RANGE	PIN-PACKAGE
MAX3831UCB*	0°C to +85°C	64 TQFP-EP
MAX3832UCB	0°C to +85°C	64 TQFP-EP

<sup>\*</sup> Future product—contact factory for availability.

## **Typical Operating Circuit**



MIXIM

Maxim Integrated Products 1

#### **ABSOLUTE MAXIMUM RATINGS**

Positive Supply Voltage (VCC)	0.5V to +5.0V
Input Voltage (LVDS, TTL)	0.5V to (VCC + 0.5V)
CML Input Voltage	( $V_{CC}$ - 0.5V) to ( $V_{CC}$ + 0.5V)
FIL+, FIL- Voltage	0.5V to (V <sub>CC</sub> + 0.5V)
TTL Output Voltage	0.5V to (Vcc + 0.5V)
LVDS Output Voltage	0.5V to (V <sub>CC</sub> +0.5V)
CML Output Currents	22mA

Note 1: Based on empirical data from the MAX3831/MAX3832 EV kit.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

#### DC ELECTRICAL CHARACTERISTICS

(VCC = +3.0V to +3.6V, LVDS differential load =  $100\Omega$  ±1%, CML load =  $50\Omega$  ±1% to VCC, CML input common-mode voltage = VCC - 0.2V, all TTL inputs are open, TA = 0°C to +85°C, unless otherwise noted. Typical values are at TA = +25°C and VCC = +3.3V.)

PARAMETER	SYMBOL	CONDITIONS		MIN	TYP	MAX	UNITS
Outside Outside		CML inputs and outputs open,	MAX3831		440	580	A
Supply Current	Icc	LVDS input V <sub>OS</sub> = 1.2V (Note 2)	MAX3832		480	614	— mA
LVDS INPUTS AND OUTPUTS	•		1				
Input Voltage Range	VIN			0		2400	mV
Differential Input Threshold	V <sub>IDTH</sub>			-100		+100	mV
Threshold Hysteresis	VHYST				90		mV
Input Impedance	RIN			85	100	115	Ω
Input Common-Mode Current	los	LVDS input, V <sub>OS</sub> = 1.2V			270		μΑ
Output Voltage High	VoH					1.475	V
Output Voltage Low	V <sub>OL</sub>			0.925			V
Differential Output Voltage	IVOD	Figure 1		250		400	mV
Change in Magnitude of Differential Output Voltage for Complementary States	ΔIVODI					±25	mV
Output Offset Voltage	Vos			1.125		1.275	V
Change in Magnitude of Output Offset Voltage for Complementary States	ΔIVOSI					±25	mV
Differential Output Iron adapas		TRIEN = GND			>1		MΩ
Differential Output Impedance		TRIEN = VCC		80		120	Ω
Output Current		Short outputs together (Note 3)				12	mA
CML INPUTS AND OUTPUTS	•						
Differential Output Voltage	V <sub>ODp-p</sub>			640	800	1000	mVp-p
Differential Output Impedance				85	100	115	Ω
Output Common Mode Voltage					V <sub>CC</sub> - 0.2	)	V
Single-Ended Input Voltage Range	VIS			V <sub>CC</sub> - 0.6		V <sub>CC</sub> + 0.2	V
Differential Input Voltage Swing		Figure 2		400		1200	mVp-p
Differential Input Impedance				85	100	115	Ω

#### DC ELECTRICAL CHARACTERISTICS (continued)

 $(V_{CC} = +3.0 \text{V to } +3.6 \text{V}, \text{LVDS} \text{ differential load} = 100 \Omega \pm 1\%, \text{CML load} = 50 \Omega \pm 1\% \text{ to } V_{CC}, \text{CML input common-mode voltage} = V_{CC} - 0.2 \text{V}, \text{all TTL inputs are open, } T_A = 0^{\circ}\text{C to } +85^{\circ}\text{C}, \text{ unless otherwise noted.}$  Typical values are at  $T_A = +25^{\circ}\text{C}$  and  $V_{CC} = +3.3 \text{V}.)$ 

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS
TTL INPUTS AND OUTPUTS			•			
Input Voltage High	VIH		2.0			V
Input Voltage Low	V <sub>IL</sub>				0.8	V
Input Current High	liH	V <sub>IH</sub> = 2.0V	-250		-50	μΑ
Input Current Low	lir	V <sub>IL</sub> = 0	-550		-100	μΑ
Output Voltage High	Voн	IOH = 20µA	2.4			V
Output Voltage Low	Vol	I <sub>OL</sub> = 2mA			0.4	V
Output Impedance		TRIEN = GND		6		kΩ

Note 2: When TEST = GND, the pattern generator will consume an additional 30mA.

Note 3: Guaranteed by design and characterization.

#### **AC ELECTRICAL CHARACTERISTICS**

 $(V_{CC} = +3.0 \text{V to } +3.6 \text{V}, \text{LVDS} \text{ differential load} = 100 \Omega \pm 1\%, \text{CML load} = 50 \Omega \pm 1\% \text{ to } V_{CC}, \text{CML input common-mode voltage} = V_{CC} - 0.2 \text{V}, \text{all TTL inputs are open, } T_A = 0^{\circ}\text{C} \text{ to } +85^{\circ}\text{C}, \text{ unless otherwise noted.}$  Typical values are at  $T_A = +25^{\circ}\text{C}$  and  $V_{CC} = +3.3 \text{V}.)$  (Note 4)

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS	
4:1 MULTIPLEXER WITH CLOCK GENERATOR							
Parallel Input Data Rate				622.08		Mbps	
Maximum Parallel Input Skew	tes	(Note 5)		±7.5		ns	
Serial-Data Output Rate				2.48832		Gbps	
Serial-Data Output Rise/Fall Time	tr, tf	20% to 80%			120	ps	
Serial-Data Output Random Jitter	SRJ	(Note 6)			3.5	psrms	
Serial-Data Output haridom sitter	SNJ	(11016.0)			40	ps <sub>p-p</sub>	
Serial-Data Output Deterministic Jitter	SDJ	(Note 7)		8	18	ps <sub>p-p</sub>	
1:4 DEMULTIPLEXER	ı		1				
Serial-Data Input Rate				2.48832		Gbps	
Serial-Data Setup Time	tsu		100			ps	
Serial-Data Hold Time	tн		100			ps	
Parallel-Data Output Rate	PDO±			622.08		Mbps	
Parallel-Clock Output Frequency	PCLKO±	MAX3831		622.08		MHz	
raialier-clock Output Frequency	FULNU±	MAX3832		155.52		IVIITZ	
PCLKO to PDO_ Delay	tclk-q	MAX3831		50		ps	
LVDS Output Rise/Fall Time		20% to 80%			350	ps	
LVDS Differential Skew	tskew1	Any differential pair			65	ps	
LVDS Channel-to-Channel Skew	tskew2	PDO1± to PDO4±		<100		ps	
LVDS Three-State Enable Time				30		ns	

Note 4: AC characteristics are guaranteed by design and characterization.

Note 5: Relative to the positive edge of the 155MHz reference clock. PDI1 to PDI4 aligned to RCLKI at reset.

Note 6: Measured with a reference clock jitter of <1ps<sub>RMS</sub>.

Note 7: Deterministic jitter is the arithmetic sum of pattern-dependent jitter and pulse-width distortion.

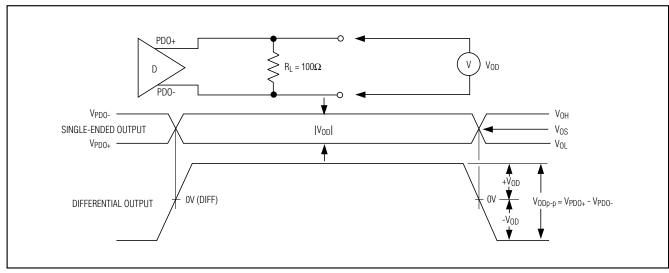


Figure 1. Definition of the LVDS Output

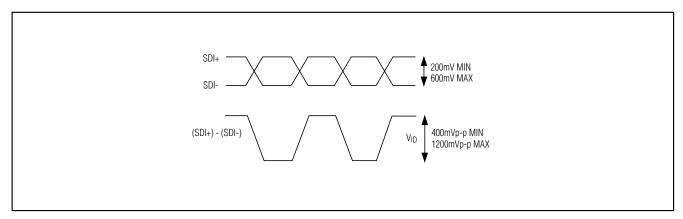
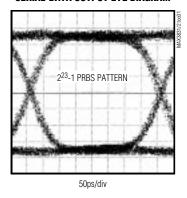


Figure 2. Definition of CML Input

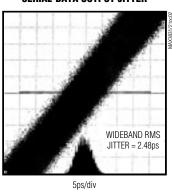
#### **Typical Operating Characteristics**

 $(V_{CC} = +3.3V, T_A = +25^{\circ}C, \text{ unless otherwise noted.})$ 

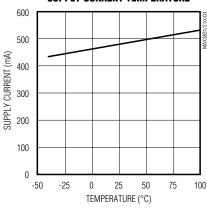
#### SERIAL-DATA OUTPUT EYE DIAGRAM



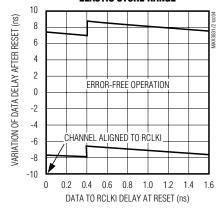
#### SERIAL-DATA OUTPUT JITTER



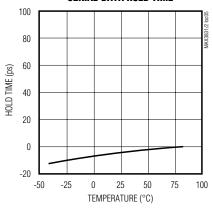
#### SUPPLY CURRENT TEMPERATURE



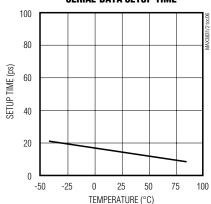
#### **ELASTIC STORE RANGE**



#### SERIAL-DATA HOLD TIME



#### SERIAL-DATA SETUP TIME



#### **Pin Description**

PIN	NAME	FUNCTION
1, 16, 25, 28, 29, 32, 43, 48, 49, 60, 63	GND	Supply Ground
2, 5, 10, 13, 17, 24, 38, 55, 59, 64	Vcc	+3.3V Supply Voltage
3	SDO-	Negative CML Serial-Data Output, 2.488Gbps
4	SDO+	Positive CML Serial-Data Output, 2.488Gbps
6	LBEN	Line Loopback Enable. When this TTL input is forced low, the CML serial-data inputs (SDI $\pm$ ) route directly to the CML serial-data outputs (SDO $\pm$ ). No other inputs or outputs are affected. An internal 15k $\Omega$ pull-up resistor pulls $\overline{\text{LBEN}}$ high for normal operation. See <i>Test Loopbacks</i> .

## Pin Description (continued)

PIN	NAME	FUNCTION
7	TEST	Self-Test Enable. When this TTL input is forced low, the built-in pattern generator generates a standard OC-12 SONET-like frame of 12 A1s, 12 A2s, and 9696 bytes of $2^7$ - 1 pseudorandom bits. This also enables an internal serial-system-loopback path. The CML inputs (SDI± and the SCLK±) and the LVDS inputs are ignored in this mode. An internal 15k $\Omega$ pullup resistor pulls $\overline{\text{TEST}}$ high for normal operation.
8	SDI+	Positive CML Serial-Data Input, 2.488Gbps
9	SDI-	Negative CML Serial-Data Input, 2.488Gbps
11	SCLKI+	Positive CML Serial-Clock Input, 2.488GHz
12	SCLKI-	Negative CML Serial-Clock Input, 2.488GHz
14	PCLKO-	Negative LVDS Parallel-Clock Output, 622.08MHz (MAX3831); 155.52MHz (MAX3832)
15	PCLKO+	Positive LVDS Parallel-Clock Output, 622.08MHz (MAX3831); 155.52MHz (MAX3832)
18-23, 26, 27	N.C.	No Connection
30	RSETFR	Frame Reset. When this TTL input is forced low, the frame detector and pattern generator are reset. The $\overline{\text{LOF}}$ output is also asserted low. An internal 15k $\Omega$ pull-up resistor pulls RSETFR high for normal operation.
31	LOF	TTL Loss-of-Frame Output. Asserts low in a loss-of-frame condition.
33	TRIEN	3-State Enable. When this TTL input is forced low, all TTL and LVDS outputs go into a high-impedance state. An internal $15k\Omega$ pull-up resistor pulls $\overline{\text{TRIEN}}$ high for normal operation.
34, 36, 39, 41	PDO4- to PDO1-	Negative LVDS Parallel-Data Output, 622Mbps
35, 37, 40, 42	PDO4+ to PDO1+	Positive LVDS Parallel-Data Output, 622Mbps
44, 46, 50, 52	PDI4- to PDI1-	Negative LVDS Parallel-Data Input, 622Mbps
45, 47, 51, 53	PDI4+ to PDI1+	Positive LVDS Parallel-Data Input, 622Mbps
54	PLBEN	Parallel System Loopback Enable. When this TTL input is forced low, the LVDS parallel inputs route through the elastic store to the LVDS parallel outputs. This bypasses the high-speed mux and demux. An internal $15 \text{k}\Omega$ pull-up resistor pulls $\overline{\text{PLBEN}}$ high for normal operation.
56	RCLKI-	Negative LVDS Reference Clock Input, 155.52MHz
57	RCLKI+	Positive LVDS Reference Clock Input, 155.52MHz
58	RSETES	Elastic Store Reset. The elastic buffer is centered on a rising edge of $\overline{\text{RSETES}}$ , maximizing the elastic store range. Data must be present for 10 $\mu$ s before applying a pulse of at least 10ns. An internal 15 $\mu$ 0 pull-up resistor pulls $\overline{\text{RSETES}}$ high for normal operation.
61	FIL-	Negative PLL Filter Capacitor Input. Connect a 0.33µF capacitor between FIL+ and FIL
62	FIL+	Positive PLL Filter Capacitor Input. Connect a 0.33µF capacitor between FIL+ and FIL
EP	Exposed Paddle	Ground. This must be soldered to a circuit board for proper thermal performance (see <i>Package Information</i> ).

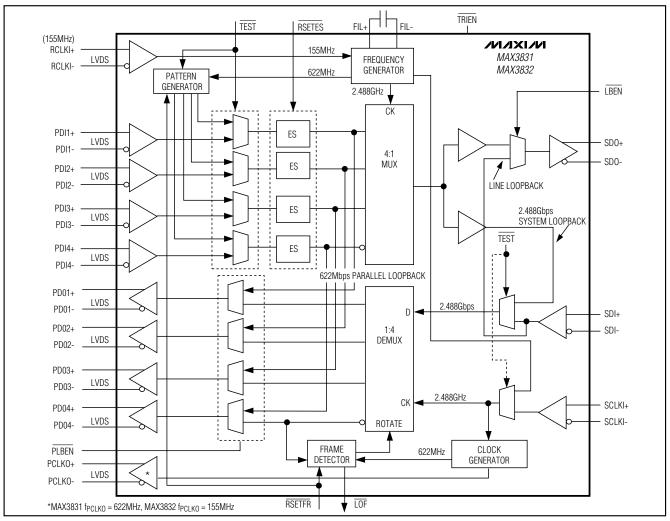


Figure 3. Functional Diagram

#### **Detailed Description**

The MAX3831/MAX3832 use a 4:1 mux and 1:4 demux with an elastic store buffer to simplify SDH/SONET interconnect I/O routing. The 622Mbps LVDS parallel inputs pass through the 10-bit elastic store buffer, which accommodates ±7.5ns skew on any single input relative to the 155MHz reference clock input RCLKI. This reference clock is required to synthesize the internal 2.488GHz clock used to drive the elastic store and 4:1 multiplexer. All TTL and LVDS outputs can be placed in a high-impedance state. See Figure 3 for a functional diagram.

The 4:1 mux bit-interleaves the parallel data, providing a 2.488Gbps CML serial output to the optical or electrical driver. The CML serial input receives the 2.488Gbps

data, the demux deinterleaves it to 622Mbps and sends the data to the frame detector. The frame detector rolls the demux into the proper channel assignment. The MAX3831/MAX3832 include high-speed, built-in self-test (BIST), which also allows testing of the 622Mbps parallel-system loopback and the 2.488Gbps line loopback.

#### **Elastic Store Buffer**

Each parallel data input, PDI1 to PDI4, passes through its respective 10-bit elastic store buffer. Following an elastic store reset, this buffer accommodates ±7.5ns of skew on any input relative to the 155MHz reference clock. Figure 4 illustrates the elastic store buffer relationship with RCLKI. The Elastic Store Range graph in the *Typical Operating Characteristics* shows the amount of data skew tolerated.

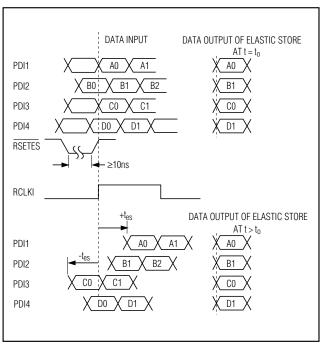


Figure 4. Example of Elastic Store Function

Following a 10µs power-up period, the locations of the individual data-channel bit transitions are acquired, guaranteeing data preservation. The output of this block passes directly into the 4:1 mux. After power-up, the elastic store buffer must be reset by applying a low pulse on RSETES for at least 10ns.

Due to the inherent uncertainty of the data transitions between the parallel-data inputs there is no bit or frame alignment between these inputs. However, the demux ensures proper channel assignment is maintained.

#### Bit-Interleaved Multiplexer/ Demultiplexer

The MAX3831/MAX3832 use a bit interleave/deinterleave mux/demux. To guarantee channel assignment, one of the four channels is inverted before multiplexing to provide a reference for the frame detector during demultiplexing. After demultiplexing, the same channel is inverted back to the original data format.

#### Frame Detector

After a 2.5Gbps serial data is bit deinterleaved into four 622Mbps channels, an SDH/SONET frame detector monitors the fourth channel, looking for the 32-bit pattern (A1A1A2A2) in the OC-12 header. To maintain correct channel assignment, the demux outputs rotate until this 32-bit overhead pattern is reliably detected. A loss-

of-frame output,  $\overline{\mathsf{LOF}}$ , indicates when the received data is in or out of frame. When  $\overline{\mathsf{LOF}}$  goes high, the frame pattern is detected and the demux outputs are correctly assigned. When  $\overline{\mathsf{LOF}}$  is low, the frame detection circuitry is searching for the correct frame. A  $\overline{\mathsf{RSETFR}}$  (TTL, active low) is included to reset the frame detector when necessary.

The frame detector uses an algorithm to detect an inframe condition and a loss-of-frame condition; this algorithm is implemented to meet the SONET in-frame and false-frame specs. The frame\_search state will occur upon start-up or reset. In this state, the frame detector scans through the incoming serial data searching for the framing pattern in the channel 4 output of the demux. While in this state, if the framing pattern is not found within 250µs, the demux channels are shifted (rolled) and the frame search continues (Figure 5).

In-frame will be declared if two consecutive framing patterns are found at the correct byte locations within the SONET frame (9720 bytes). If this pattern is not present at the correct location (false frame), the state machine will return to the frame\_search state described above. While in the in\_frame state, each frame will be checked for a framing pattern at the correct location. Four consecutive false frames will cause the state machine to return to the frame\_search state described above. The false-frame counter is reset with three or fewer consecutive false frames.

## Built-In Self-Test (BIST) with On-Chip Serial Loopback

An on-chip pattern generator can be enabled to produce a 622Mbps SDH/SONET-like transport overhead followed by a pseudorandom bit sequence. This consists of 12 A1s, 12 A2s, and a pseudorandom bit stream (PRBS =  $2^7$  - 1). When  $\overline{\text{TEST}}$  is low, this pattern is distributed to all parallel inputs, bypassing the LVDS input buffers. Note, this pattern is skewed by one 622MHz clock cycle between each channel. In this test mode, serial data is internally looped back to the demux. All frame detect logic is exercised using this mode. The CML inputs (SDI± and SCLKI±) and LVDS inputs (PDI\_±) are ignored in this mode. After the BIST mode is enabled, the loss-of-frame flag LOF goes high, indicating that the selftest has passed. In normal operation, TEST is left open (internally pulled high), disabling the pattern generator and accepting data from the parallel input channels.

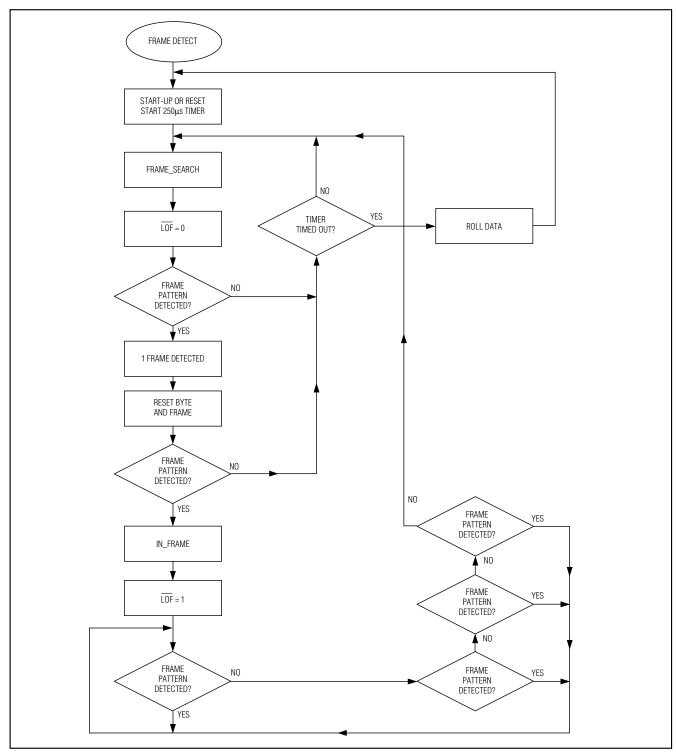


Figure 5. Frame Detection Flow Diagram

#### **Test Loopbacks**

Two additional test loopbacks are provided: parallel system loopback and serial line loopback.

#### Parallel System Loopback

In parallel system loopback, four 622Mbps parallel input channels are phase aligned by an associated 10-bit elastic store and routed to the output LVDS buffers. This loopback is controlled by setting PLBEN low. Normal data transmission is resumed when PLBEN goes high (internally pulled high).

#### Serial Line Loopback

Serial line loopback is used for testing the performance of the optical transceiver and the transmission link. The received 2.488Gbps data stream is routed to the transmit CML output buffer. Line loopback is enabled when LBEN is asserted low. When LBEN is left open (internally pulled high), normal serial-data transmission resumes.

#### **LVDS Parallel Interface**

The MAX3831 parallel interface includes four OC-12 data inputs, a 155MHz reference clock input, four 622Mbps parallel-data outputs, and a 622MHz parallel-clock output (MAX3832, fpclko = 155MHz). All parallel inputs and outputs are LVDS compatible to minimize power dissipation, speed transition time, and improve noise immunity. The 155MHz input signal at RCLKI requires a duty cycle between 40% and 60%.

The LVDS outputs go into a high-impedance state when TRIEN is forced low. This simplifies system checks by allowing vectors to be forced on the LVDS outputs.

#### **CML Serial Interface**

The MAX3831/MAX3832 provide a 2.488Gbps serial-data stream to a driver and accept 2.488Gbps serial-data and a 2.488GHz clock signal from an external clock and data recovery device (MAX3876). The high-speed interface is CML compatible, resulting in lower system power dissipation and excellent performance (Figure 6).

## \_Applications Information

#### Low-Voltage Differential Signal Inputs/Outputs

The MAX3831/MAX3832 have low-voltage differential signal (LVDS) inputs and outputs for interfacing with high-speed digital circuitry. All LVDS inputs and outputs are compatible with the IEEE 1596.3 LVDS specification. This technology uses 250mV to 400mV differential low-voltage swings to achieve fast transition times, minimize power dissipation, and improve noise immunity.

For proper operation, the parallel clock and data LVDS outputs (PCLKO+, PCLKO-, PDO\_+, PDO\_-) require  $100\Omega$  differential DC termination between the inverting and noninverting outputs. Do not terminate these outputs to ground. The parallel-data LVDS inputs (PDI\_+, PDI\_-) are internally terminated with  $100\Omega$  differential input resistance and therefore do not require external termination.

#### Interfacing with PECL/ECL Input Levels

When interfacing with differential PECL input levels, it is important to attenuate the signal while still maintaining  $50\Omega$  termination (Figures 7 and 8). Observe the common-mode input voltage specifications. AC-coupling is required if a VCC other than 3.3V is used to maintain the input common-mode level (Figure 7).

#### **Layout Techniques**

For best performance, use good high-frequency layout techniques. Filter voltage supplies, keep ground connections short, and use multiple vias where possible. Use controlled-impedance transmission lines to interface with the MAX3881/MAX3882 high-speed inputs and outputs.

Place power-supply decoupling as close to V<sub>CC</sub> as possible. To reduce feedthrough, take care to isolate the input signals from the output signals.

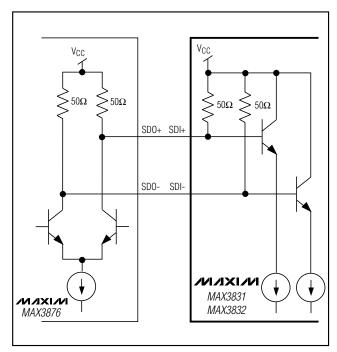


Figure 6. CML-to-CML Interface

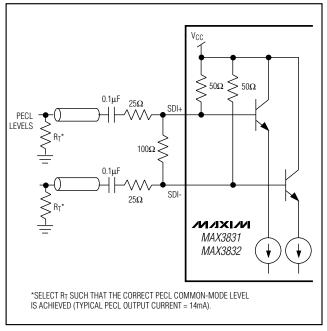


Figure 7. PECL-to-CML Interface

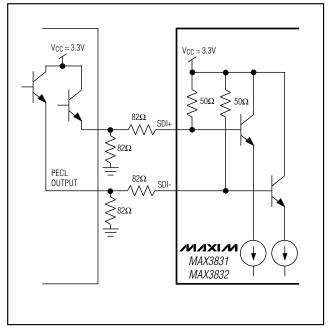
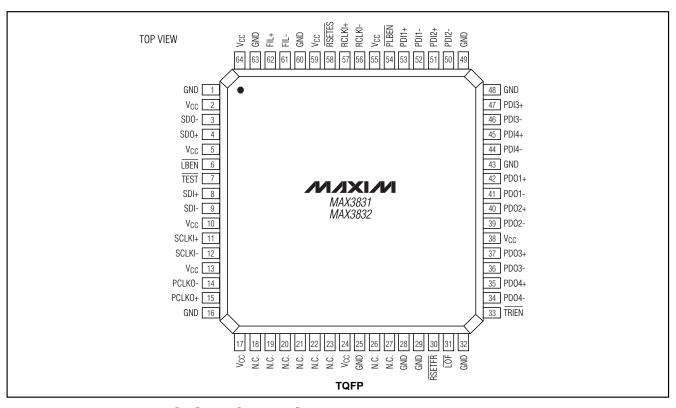


Figure 8. Direct Coupling of a PECL Output into the MAX3831/MAX3832

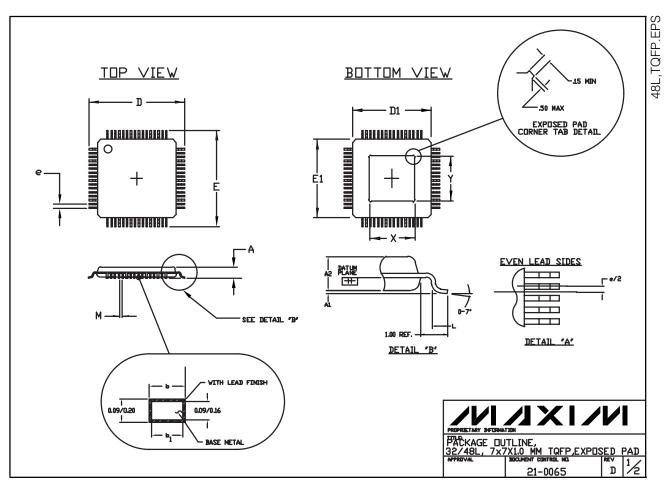
#### **Pin Configuration**



**Chip Information** 

TRANSISTOR COUNT: 14,134

## **Package Information**



#### Package Information (continued)

#### NOTES:

- 1. ALL DIMENSIONING AND TOLERANCING CONFORM TO ANSI Y14.5-1982.
- 2. DATUM PLANE ——— IS LOCATED AT MOLD PARTING LINE AND COINCIDENT WITH LEAD, WHERE LEAD EXITS PLASTIC BODY AT BOTTOM OF PARTING LINE.
- 3. DIMENSIONS D1 AND E1 D0 NOT INCLUDE MOLD PROTRUSION. ALLOWABLE MOLD PROTRUSION IS 0.254 MM ON D1 AND E1 DIMENSIONS.
- ALLOWABLE MOLD PROTRUSION IS 0.254 MM ON DI AND EI
  4. THE TOP OF PACKAGE IS SMALLER THAN THE BOTTOM
  OF PACKAGE BY 0.15 MILLIMETERS.
  5. DIMENSION & DOES NOT INCLUDE DAMBAR PROTRUSION.
  ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.08mm TOTAL
  IN EXCESS OF THE & DIMENSION AT MAXIMUM MATERIAL
  CONDITION.
  6. CONTROLLING DIMENSION MILLIMETER.
  7. THIS DUTLINE CONFIRMS TO JEDEC PUBLICATION 95
  REGISTRATION MO-136, VARIATIONS AC AND AE.
  8. EXPOSED DIE PAD SHALL BE COPLANAR WITH BOTTOM
  OF PACKAGE WITHIN 2 MILS (.05 MM).
  9. LEADS SHALL BE COPLANAR WITHN JOA INCH.

S	JEDEC VARIATION ALL DIMENSIONS IN MILLIMETERS							
M B	AC AE							
l י	MIN.	N□M.	MAX.	MIN. NOM. MAX				
Α	N.	75c	1.20	N.	75c	1.20		
A <sub>1</sub>	0.05	0.10	0.15	0.05	0.10	0.15		
Az	0.95	1.00	1.05	0.95	1.00	1.05		
ם		9.00 BSC. 9.00 BSC.						
D <sub>1</sub>	7.00 BSC. 7.00 BSC.							
E	9.00 BSC. 9.00 BSC.							
E <sub>1</sub>		7.00 BSC. 7.00 BSC.						
L	0.45	0.60	0.75	0.45	0.60	0.75		
M	0.15	74	- Xe	0.14	1/2	1/2		
N		32			48			
e		0.80 BSC. 0.50 BSC.						
lo	0.30	0.37	0.45	0.17	0.22	0.27		
lo1	0.30	0.35	0.40	0.17 0.20 0.23				
x	3.20	3.50	3.80	3.70 4.00 4.30				
Υ	3.20	3.50	3.80	3.70	4.00	4.30		

PROPRIETARY INFORMA			
PACKAGE DU 32/48L, 7x7	TLINE. ×1.0 MM TQFP, EXPO	SED I	PAD
APPROVAL	SOCUMENT CONTROL NO.	REV	2/
	21-0065	D	⁄2

# MAX3831/MAX3832

# +3.3V, 2.5Gbps, SDH/SONET, 4-Channel Interconnect Mux/Demux ICs with Clock Generator

**NOTES** 

/N/1XI/M \_\_\_\_\_

**NOTES** 

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